

PA-IDC

QUERY CONTROL FORM		RTIS USE ONLY
Application No.	Prepared by	Tracking Number
Examiner-GAJ	Date	Week Date
<u>09/0019407</u>	<u>SPM</u>	<u>05875029</u>
<u>Bruce - 2882</u>	<u>4/8/04</u>	<u>12/12/03</u>
	No. of queries	(Initials)
	<u>1</u>	<u>TGJ</u>

JACKET

a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

MESSAGE PTO1449: Please either initial or
line through citations. Copy provided for
reference.

CLAIMS

- a. Claim(s) Missing
- b. Improper Dependency
- c. Duplicate Numbers
- d. Incorrect Numbering
- e. Index Disagrees
- f. Punctuation
- g. Amendments
- h. Bracketing
- i. Missing Text
- j. Duplicate Text
- k. Other

THANK you
initials 

RESPONSE

initials

initials

COPY OF PAPERS
ORIGINALLY FILED

INFORMATION DISCLOSURE CITATION <i>(Use additional sheet if necessary)</i>		Docket Number (Optional) TWI-10830	Application Number 09/629,407
		Applicant(s) Afsen Rosenzweig et al.	Filing Date August 1, 2000
		Group Art Unit 2876	

APR 30 2002

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
CA	WO 01/71325	09/27/2001	PCT	G01N	23/00		

OTHER DOCUMENTS
(Including Author, Title, Date, Pertinent Pages, Etc.)

CB	E. Lüken et al., "Growth monitoring of W/Si X-ray multilayers by X-ray reflectivity and kinetic ellipsometry," SPIE, Vol. 2253, November 1994, pp. 327-332.

Examiner	Date Considered
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include Copy of this form with next communication to applicant.	

RECEIVED
MAY -2 2002
TECHNOLOGY CENTER 2800